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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of: Kenji WATANABE et al.

Group Art Unit:

Serial Number: 10/543,151

Examiner:

Filed: July 25, 2005

Confirmation Number:

For:

MAPPING-PROJECTION-TYPE ELECTRON BEAM APPARATUS FOR

INSPECTING SAMPLE BY USING ELECTRONS EMITTED FROM THE

SAMPLE

Attorney Docket Number:

052886

Customer Number:

38834

INFORMATION DISCLOSURE STATEMENT UNDER 37 C.F.R. §1.97(b)

Commissioner for Patents P. O. Box 1450 Alexandria, VA 22313-1450 December 23, 2005

Sir:

In compliance with 37 C.F.R. §1.56, Applicants direct the attention of the Patent and Trademark Office to the documents listed on the attached PTO/SB/08. This paper is being filed within the time periods set forth in 37 C.F.R. §1.97(b). A copy of each non-U.S. document is enclosed herewith.

The inventor considers Japanese Laid-open No. Hei 4-242060 to disclose a reflection election microscope having a similar electron beam deflection device.

If there are any fees due in connection with the filing of this paper, please charge Deposit Account No. 50-2866.

Respectfully submitted,

WESTERMAN, HATTORI, DANJELS & ADRIAN, LLP

Attorney for Applicants Registration No. 32,878

Stephen G. Adrian

Telephone: (202) 822-1100 Facsimile: (202) 822-1111

SGA/arf

Enclosures:

PTO/SB/08

3 Documents

C 1: 12 PMO(CD/00 4 C D				Complete if Known			
Combined Form PTO/SB/08A&B				Application Number	10/543,151		
INFORM	ATION DIS	CLOS	JRE	Confirmation Number			
STATEMENT BY APPLICANT				Filing Date	July 25, 2005. 04-18-200		
23 2005 gg (use as many sheets as necessary)				First Named Inventor	Kenji WATANABE et al.		
(use as	many sheets as n	iecessarı	·)	Art Unit	2881		
				Examiner Name	K. Nguyen		
Sheet	1	of	1	Attorney Docket Number	052886		

U.S. PATENT DOCUMENTS						
Examiner Initials*	Cita	Document	Number	Publication Date MM-DD-YYYY		
	Cite No. ¹	Number	Kind Code ² (if known)		Name of Patentee or Applicant of Cited Document	
	1	US 5,576,833		11/19/1996	Miyoshi et al.	
		US				
		US				
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FOREIGN PATENT DOCUMENTS							
Examiner Cite	Cite	Foreign Patent Document			Publication Date	Name of Patentee or	
Initials*	No.1	Country Code ³	Number ⁴	Kind Code ⁵ (if known)	MM-DD-YYYY	Applicant of Cited Document	Translation ⁶
	2	JР	4-242060		08/28/1992		_
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NON PATENT LITERATURE DOCUMENTS				
Examiner Initials*	Cite No.1	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city, and/or country where published.	Translation ⁶	
	3	K. Tsuno, "Simulation of a Wien filter as beam separator in a low energy electron microscope", pp. 127-140, Ultramicroscopy 55 (1994).		
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	/Kiet Tuan Nguyen/		l 08/17/2008 l
Everniner Signature	/ Not rout rigayon	Date Considered	
Examiner Signature		Date Constacted	

^{*}EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹Applicant's unique citation designation number (optional). ²See Kind Codes of USPTO Patent Documents at www.uspto.gov, MPEP 901.04 or in the comment box of this document. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST. 3). ⁴For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶ Applicant is to indicate here if English language Translation is attached.